OXYGEN@200 MEV/N CROSS SECTION EVALUATION AND COMPARISON WITH LITERATURE



A. Alexandrov, V. Boccia, A. Di Crescenzo, G. De Lellis, G. Galati, A. Iuliano, A. Lauria, <u>M. C. Montesi</u>, A. Pastore, V. Tioukov

Università di Napoli "Federico II", INFN Napoli, Università di Bari, INFN Bari

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Analysis Status



Reaction cross-section measurement (integrated):

 $^{16}\!O \ensuremath{\,@}\xspace{0.5ex} 200 \ MeV/n \ on \ C \ and \ C_2H_4 \ target$

Energy (MeV/n)	mBarn C ₂ H ₄	mBarn C	mBarn H
185	3,266	1,096	0,269
160	3,093	1,179	0,184
140	3,216	1,144	0,232

Analysis Status

COMPARISON WITH LITERATURE DATA:

- HTTPS://GSI.DE/FRAGMENTATION (DATABASE ON LINE FROM F. LUONI ET AL., TOTAL NUCLEAR CROSS-SECTION DATABASE FOR RADIOTION PROTECTION IN SPACE AND HEAVY-ION THERAPY APPLICATION, NEW J. PHYS., VOL 23, 101201, 2021)
- ➤ W.R. WEBBER ET AL., TOTAL CHARGE AND MASS CHANGING CROSS SECTION OF RELATIVISTIC NUCLEI IN HYDROGEN, HELIUM AND CARBON TARGETS, PHYSICAL REVIEW C, VOL. 41, NO. 2, PAG. 520-532, 1990
- ➤ C. ZEITLIN ET AL., FRAGMENTATION OF ¹⁴N,¹⁶O, ²⁰NE AND ²⁴MG NUCLEI AT 290 TO 1000 MEV/NUCLEON, PHYSICAL REVIEW C, VOL. 83, 034909, 2011
- YAMAGUCHI ET AL., SCALING OF CHARGE-CHANGING INTERACTION CROSS SECTIONS AND POINT-PROTON RADII OF NEUTRON-RICH CARBON ISOTOPES, PHYS. REV. LETT. 107, 032502, 2011

 $\checkmark \sigma(H) = 0.5 [\sigma(O^{16}->CH_2) - \sigma(O^{16}->C)] = 232 \text{ mbarn (formula from Webber, @441 MeV)}$

 $\checkmark \sigma(H) = 0.25 [\sigma(O^{16} > C_2H_4) - 2 \sigma(O^{16} > C)] = 230 +/-40 \text{ mbarn (our data, @ 160 MeV)}$

Improvement in cross section evaluation

$$\frac{d\sigma(x)}{dx}\Big|_{C \text{ or } C_2H_4} = \underbrace{\begin{array}{c}Y_i(x)\\N_B N_{TG}\Delta x \epsilon^i_{reco}(x)\end{array}}_{V_i = \# \text{ of } f_i} \bullet N_B = \# \text{ of } f_i \bullet N_{TG} = \# \text{ of }$$

Y_i =# of fragments in the interval Δx
N_B =# of ions colliding on the target
N_{TG} =# of particles in the target
Δx = x bin
εⁱ_{reco} = reconstruction efficiency



- Each passive material layer acts as a new target and can be considered a "new measurement"
- The number of incident beam particle on each layer has to be evaluated and is affected by its efficiency ($N_{Bi} = N_{tot} (VX_{B1} + VX_{B2} + VX_{B(i-1)})$; VX_{Bi} number of vertex in the *i* layer)
- We have not already taken into account the efficiency in the VX_{Bi} determination

ON GOING

- 1) Cross section evaluation @400 MeV/n
- 2) PAPER ON CHARGE IDENTIFICATION: ¹⁶O @ 200 MeV/N and 400 MeV/N on C and C_2H_4 Target; (Frontiers; draft)

BACK UP

The emulsion spectrometer structure

